1
l

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/724,075	AKAGAWA, KEIICHI	
Examiner	Art Unit	
Tamai IE Karl	2834	

	SEAR	CHED	
Class	Subclass	Date	Examiner
310	309		•
359	290, 291		
	224		
385	16-18	7/18/2005	· KIT
			•
_			
	,		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
,			
			-1

(INCLUDING SEARCH	T	
	DATE	EXMR
·		,
•		
	,	
•		
·	 	
	<u> </u>	